

Notice of References Cited		Application/Control No. 10/585,067	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
		Examiner NICOLE M. BUIE-HATCHER	Art Unit 1796	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0228249 A1	12-2003	Fujimura et al.	423/446
	B	US-			
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NON-PATENT DOCUMENTS

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	U	translation of Savinkin et al. (RU 2164524 C1), 12/24/2009
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